A Workshop on

Measurement Methods for Evaluation of the Reliability of Active Implantable Medical Devices

October 3–4, 2005

Lecture Room B
Administration Building, Building 101
National Institute of Standards and Technology
Gaithersburg, MD 20899

Conference Chairperson

William F. Regnault U.S. Food and Drug Administration

Conference Co-chairperson

Elizabeth S. Drexler
Materials Reliability Division
National Institute of Standards and Technology

Conference Co-chairperson

John A. Tesk Biomedical Materials and Devices Consulting

Sponsored by:

US Food and Drug Administration (FDA) http://www.fda.gov/
Center for Devices and Radiological Health http://www.fda.gov/cdrh/
National Institute of Standards and Technology (NIST) http://www.nist.gov/
Materials Science & Engineering Laboratory http://www.msel.nist.gov/
Materials Reliability Division http://www.msel.nist.gov/
Polymers Division http://www.msel.nist.gov/
Manufacturing Engineering Laboratory http://www.mel.nist.gov/

With cooperation of: The American Society for Testing and Materials International (ASTM) http://www.astm.org/

Pre-registration is required, on-site registration is not available. To pre-register go to: https://rproxy.nist.gov/CRS/conf ext.cfm?conf id=1485

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Agenda

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October 3, Day 1							
8:00 AM	Registration & Continental Breakfast						
8:55 AM	Introductions, Moderator, John A. Tesk						
9:00 AM	Welcome to the Workshop, NIST & the FDA	Rich Kayser NIST					
9:10 AM	NIST & Biomaterials	Lori Henderson NIST					
9:20 AM	Introduction to the Workshop Issues	William F. Regnault FDA					
Plenary Sessions I, II & III Moderator, William F. Regnault, FDA							
9:35 AM	Plenary Session I						
9:35 AM	Patient Perceptions leading to Explantation	James Kane FDA					
10:00 AM	Post-Market Regulation of Medical Devices	Betty Collins FDA					
10:25 AM	GMP Regulations and Standards	Jan Welch FDA					
10:45 AM	BREAK	van Weien 1911					
11:00 AM	Plenary Session II – Designing for Intended Use and Relial	bility Ali Mosleh U MD					
11:30 AM	Plenary Session III – MIL-STDS and Consensus Standards – Their Utility and their						
	Inference for Device Reliability	•					
11:30 AM	What Standards are Needed?	Celeste Null Intel					
12:00 AM	Issues Surrounding the Use of Standards and Test Methods Open Discussion						
10 00 DD 5	Il. NIGT G C						
12:30 PM	Lunch, NIST Cafeteria						
12:30 PM		kler, NIST					
	Working Sessions I & II Moderator, Elizabeth S. Drex						
1:30 PM	Working Sessions I & II Moderator, Elizabeth S. Drew Working Session I—Plausible Mechanisms for Failure: Mechanisms	chanisms inside the Can					
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OCTOBE	E R 4 , DAY 2						
7:45 AM		& Continental Breakfast					
8:45 AM	•	Working Sessions III & IV Moderators; Elizabeth Drexler, NIST & John Tesk					
	Working Session III- Measurements for Accelerated Reliability Testing of						
	Packages				8		
	O	air: Stan Purwin John	ns Honkins University A	nnlied Physics I	aboratory		
8:45AM		sion Chair: Stan Purwin Johns Hopkins University Applied Physics Laboratory are the Proper Accelerators for Predicting the Reliability of Active Implantable Medical					
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9:05 AM		Advice that the Workshop Seeks (see Session Chair's Gui				
10:05 AM	BREAK						
10:20 AM	Working Se	ession IV Medical System	Concerns- Manufa	cturers' Pers	pectives		
		air: Keith McLain		Advanced B			
10:20 AM		tem Concerns – A Device Manuf	acturer's Perspective	David Erhart			
10:40 AM		d Standards and Requirements for					
		anufacturer's Perspective		elea Cochlear	Corporation		
11:00 AM	Answers for	Advice that the Workshop Seeks	(see Session Chair's Gu	ıide)			
12:00 PM	Lunch, NIS	ST Cafeteria					
1:00 PM	,						
	_	n B: <u>Session I, J. Martinez</u> , K. Rodl	bell, R.Munroe, B.Thomas				
		Session II, M. Schen, R. Baboia					
	(Room A149,	Bldg 224, Polymers: <u>Session III, S</u>		1 \			
1.00 DM	Warling C		<u>K. McLain,</u> D. Erhart, E. Cap	-			
1:00 PM	_	Session V, Reliability Issues					
	Session Cl	hair: John Suehle 1	Moderator, Elizabeth I)rexler	NIST		
Session V	is anon to all av	cept the previous session chairs	s and prosentors from (thoir cossions w	ho wish to		
	_	airs on developing Summary R	_	men sessions w	'no wish to		
)2:15 PM		n and Summary Recommendation		W F Regnau	lt FDA		
J2.1J 1 W1	Who is to do	· ·	iluations moderator,	, W. F. Kegnau	n, IDA		
		work to be done?					
		ork to be accomplished?					
		F					
	Is there a need for a follow-up workshop or symposium?						
3:00 PM:	End of Wo	rkshop					
Planning (<u>Committee</u>						
		Center for Devices and Radiolog	gical Health, FDA &				
		Guest Researcher, NIST					
Elizabeth S. Drexler,		Materials Reliability Division,	NIST				
John A. Tesk,		Consultant &					
		Guest Researcher, NIST					
Michael Schen,		. Advanced Technology Program	n, NIST				
	G 11						
<u>Workshop</u>			1 1 111 1.1 ED 4 ^				
i onya Iceno	ogle,	Center for Devices and Radiol	ogical Health, FDA &				
		Guest Researcher, NIST					

Tithi Dutta Roy,..... Postdoctoral Fellow, Biomaterials Group, Polymers Division